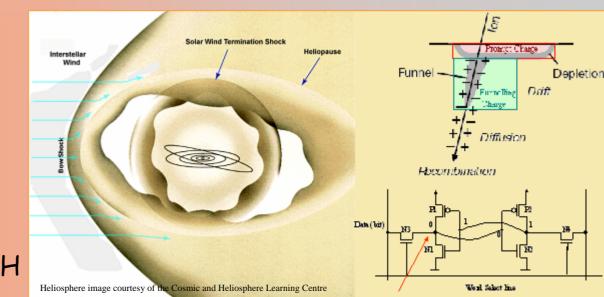


Modelling SEE on Components

CODES: <u>component degradation</u> <u>simulation</u> tool

A.Keating ESA Project: 18121/04/NL/CH









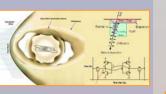
* Aim

- * Project overview
- Modelling Philosophy
- * Physics and Mechanisms
- * GEANT 4 Physics vs Device Physics



- * Device Functioning Module
- * Conclusions





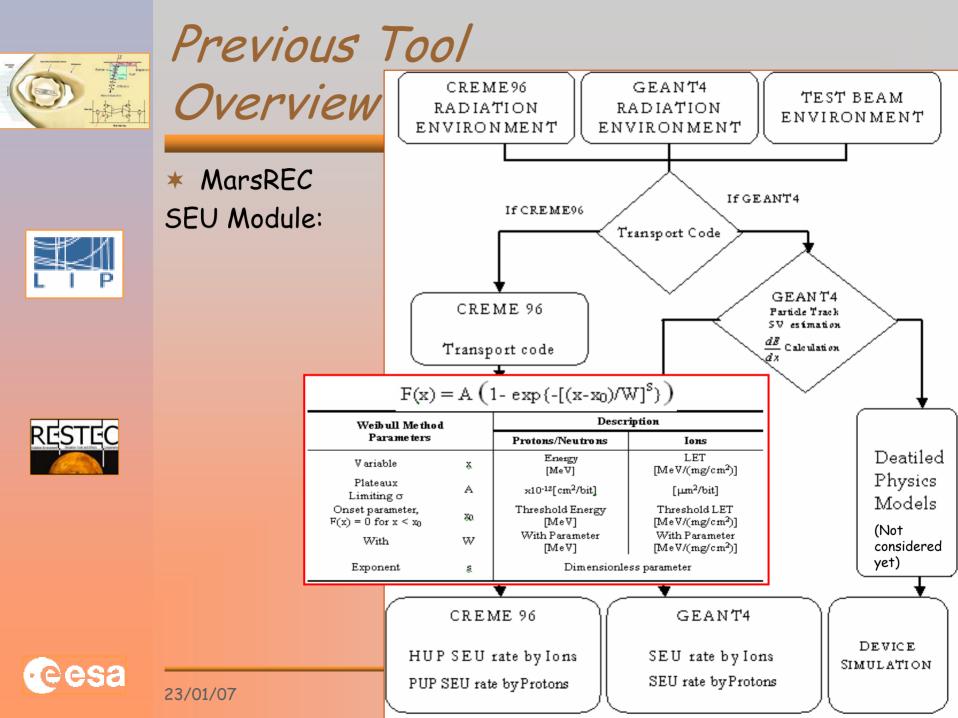
CODES aim

The current activity aims at:



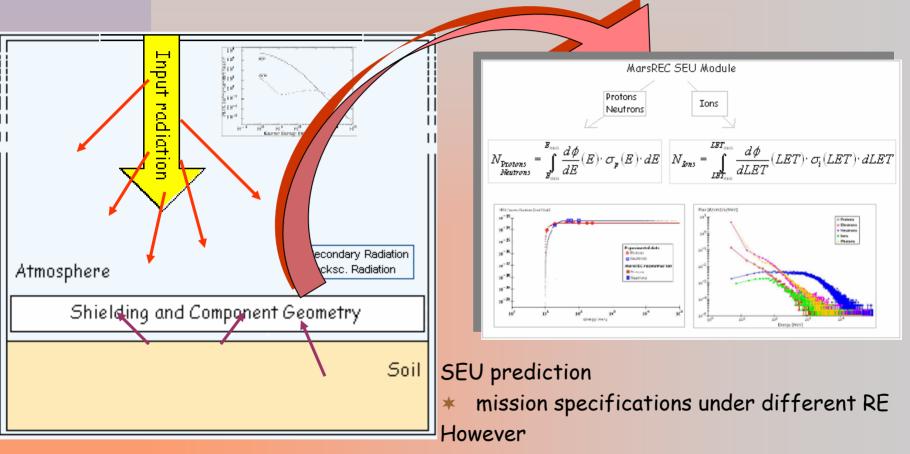
- Expanding the capabilities of previously developed component simulation tool
- * SEU rate predicting in specific components,
- Generalising it for a family of components,
- * Make it valuable for new technology scales
- * Simulation of the physics of the SEU inside the device
- * Produce experimental verification
- Allow the different radiation input scenarios







MarsREC SEU Module Philosophy



 No detailed modelling of SEE physics in the device!







- How to implement the device active behaviour in a tool capable of Monte Carlo tracking of primary and secondary particles?
- * Use Geant4 to track the interaction of the incoming radiation with the device
- Establish an interface capable of describing device physics and functioning
- * Investigate the Sensitive Volume

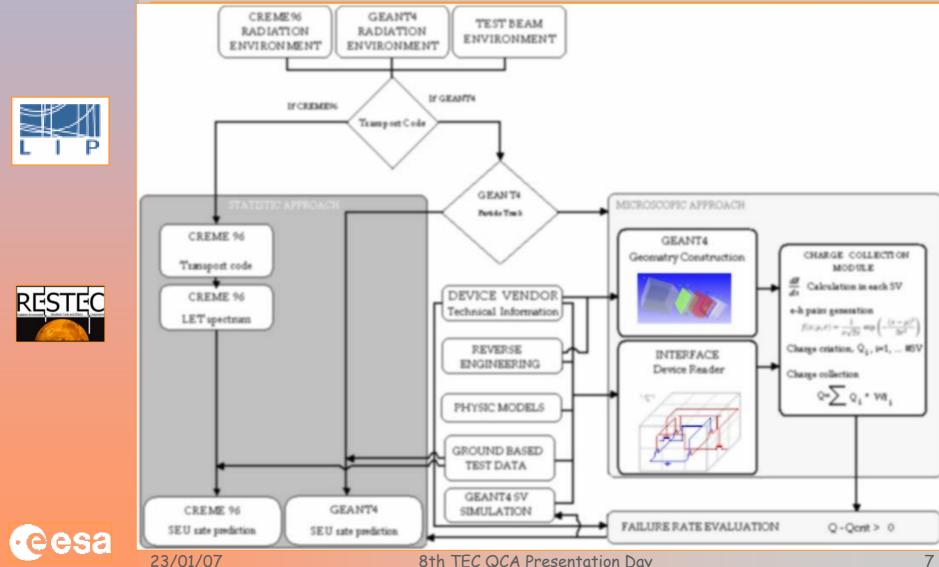




23/01/07







8th TEC QCA Presentation Day

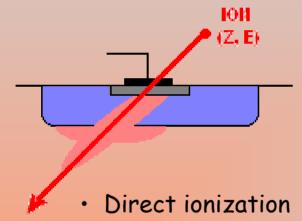


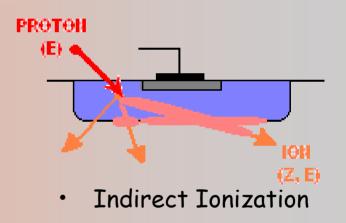
Direct and Indirect Processes

 The two distinct processes induced by ions and protons/neutrons require different analysis methods



RESTEC





- * GEANT4 allows the tracking of :
 - primary and secondary radiation
 - energy deposition





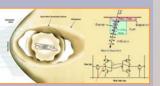
RESTE

GEANT4 Physics

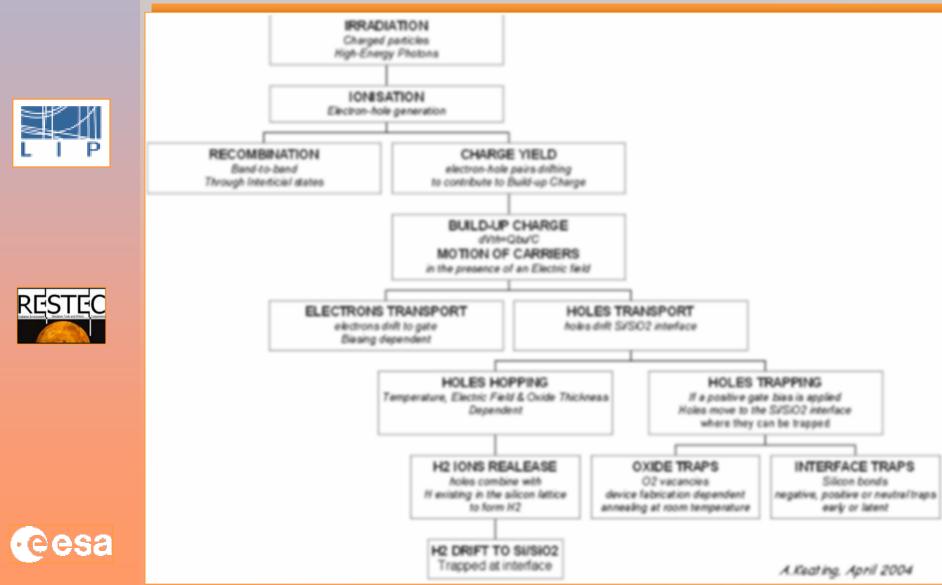
	Physics	locielis & Processes		Applications		
	Electromagnetic	Multiple	Scattering	Direct & Indirect SEE		
		Comptan				
		Rayleigh		Ionising Energy Loss	<u> </u>	/
		Electron	Ionisation		1	
Р		Muon		LET calculation		
		Hadron -				
		Ion				
		Bremsstrahlung		Th		`
		e+e- annihilations and production				
		Photo-electric effect				f
		Gamma conversion				
		Coulo tool	Physics	Models & Processes		Applications
	* Monte	Carlo tool	Hadronic [Elastic		Secondary production
	* Process	ses from ~1 PeV		Precompound (2-100MeV)	T T I I	
	to ~100)eV		Bertini Cascade (< 10MeV-100		
				Binary Cascade (10MeV-~GeV) Parameterised Electromagnetic dissociation		Indirect SEE
		high-energy				
	physics	, in space				
	researc	ch, and in		Abrasion/ablation		
		medical		Gamma - and Lepto-Nudear		
				Low energy Neutrons (< 20M	leV)	
ea_					,	



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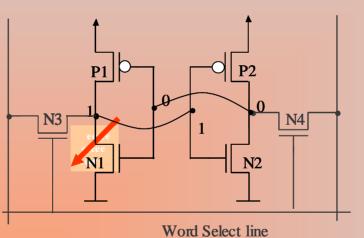


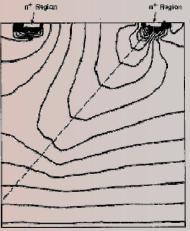
* The device behaviour depends on the field (ξ), Incoming particle LET (λ) and on the angle of incidence (θ)





$$Q_{\text{collected}} = f(\xi, \lambda, \theta) > Q_{\text{cri}}$$





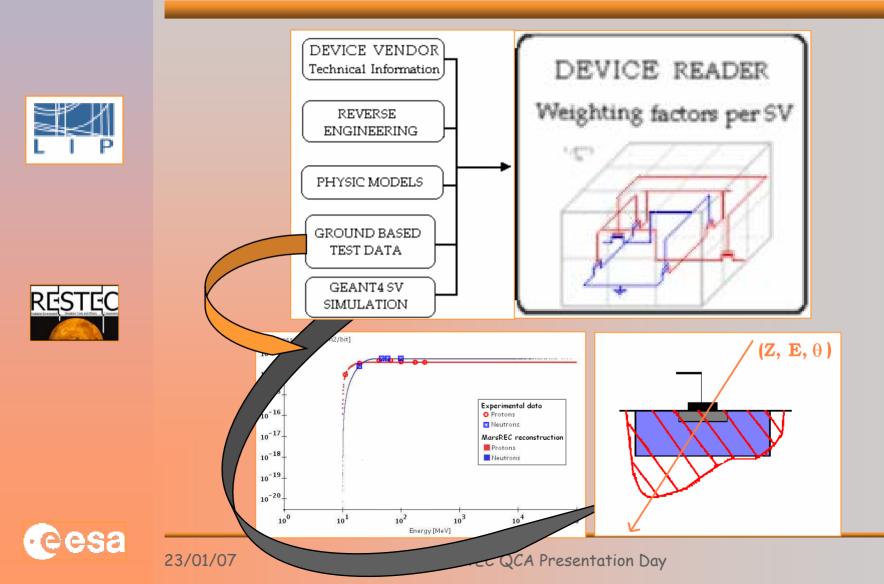
* The critical charge depends on the node capacitance, voltage and the response time of the device

$$Q_{crit} = C_{node} \cdot V_{node} + \tau_{switch} \cdot I_{restore}$$













- * CODES two years activity -Started in November 2006
- CODES Philosophy is defined
- * Powerful tool : contribute to the analysis of SEE effects

& Sensitive Volume



- The next step:
- * Implement and validate the concept using:
 - Experimental & Ground based test data,
 - Deposited Dose maps of the device
 - Reverse engineering

Positive Interaction is welcome!

